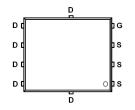
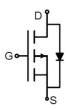


### **Main Product Characteristics:**

V <sub>DSS</sub>	-30V		
R <sub>DS</sub> (on)	1.9mΩ (typ.)		
I <sub>D</sub>	-131A		







PDFN5x6-8L

Pin Assignments

Schematic Diagram

#### **Features and Benefits:**

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



# **Description:**

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

# **Absolute Max Rating:**

Symbol	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V ①	-131	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V ①	-83	Α
I <sub>DM</sub>	Pulsed Drain Current ②	-524	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation ③	69	W
V <sub>DS</sub>	Drain-Source Voltage	-30	V
V <sub>GS</sub>	Gate-to-Source Voltage	±20	V
T <sub>J</sub> T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to +150	°C



# **Thermal Resistance**

Symbol	Characterizes	Тур.	Max.	Units
Rejc	Junction-to-case ③	_	1.8	°C/W

# **Electrical Characteristics** @T<sub>A</sub>=25℃ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source breakdown voltage	-30	_	_	V	$V_{GS} = 0V, I_D = -250\mu A$
D 04-	04-4i- Di- 4- 0	_	1.9	2.5	· O	V <sub>GS</sub> = -10V,I <sub>D</sub> = -20A
$R_{DS(on)}$	Static Drain-to-Source on-resistance	_	2.7	3.6	mΩ	V <sub>GS</sub> = -4.5V,I <sub>D</sub> = -20A
V <sub>GS(th)</sub>	Gate threshold voltage	-1	_	-2.5	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$
I <sub>DSS</sub>	Drain-to-Source leakage current	_	_	-1	μA	$V_{DS} = -30V, V_{GS} = 0V$
	Cata to Source forward lookage	_	_	100		V <sub>GS</sub> =20V
I <sub>GSS</sub>	Gate-to-Source forward leakage	_	_	-100	nA	V <sub>GS</sub> = -20V
C <sub>iss</sub>	Input capacitance	_	12750	_		V <sub>GS</sub> = 0V
Coss	Output capacitance	_	1330	_	pF	V <sub>DS</sub> = -15V
Crss	Reverse transfer capacitance	_	1200	_		f = 1MHz
Qg	Total gate charge	_	20	_		I <sub>D</sub> = -20A,
Qgs	Gate-to-Source charge	_	2.5	_	nC	V <sub>DS</sub> =-15V,
Q <sub>gd</sub>	Gate-to-Drain("Miller") charge	_	3	_		V <sub>GS</sub> = -10V
t <sub>d(on)</sub>	Turn-on delay time	_	20	_		
t <sub>r</sub>	Rise time	_	4	_		V <sub>GS</sub> =-10V, V <sub>DS</sub> =-15V,
t <sub>d(off)</sub>	Turn-Off delay time	_	23	_	ns	$R_{GEN}$ =3 $\Omega$ , $R_L$ =0.75 $\Omega$
t <sub>f</sub>	Fall time	_	37	_		

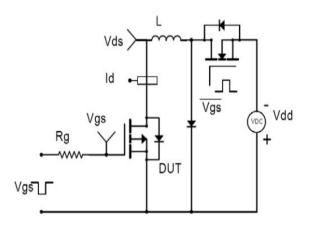
# **Source-Drain Ratings and Characteristics**

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
	Continuous Source Current			121	^	MOSFET symbol
l <sub>S</sub>	(Body Diode)	_  13	-131	A	showing the	
1	Pulsed Source Current			504	۸	integral reverse
Іѕм	(Body Diode)	_	_	—     -524	Α	p-n junction diode
V <sub>SD</sub>	Diode Forward Voltage	_	_	-1.2	V	I <sub>S</sub> =-20A, V <sub>GS</sub> =0V
t <sub>rr</sub>	Reverse Recovery Time	_	40	_	ns	$T_J = 25^{\circ}C$ , $I_F = -20A$ , $di/dt =$
Q <sub>rr</sub>	Reverse Recovery Charge	_	30	_	nC	-100A/µs

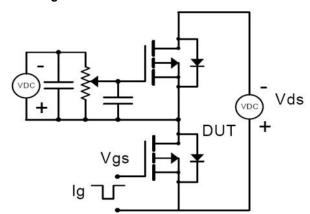


### **Test Circuits and Waveforms**

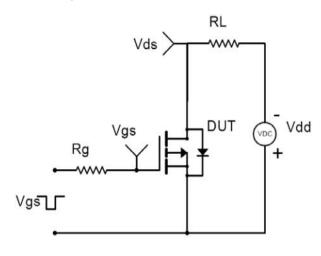
#### **EAS Test Circuit:**



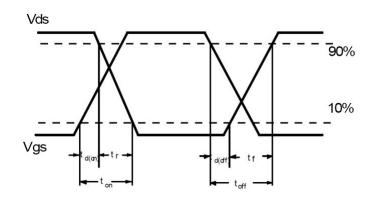
#### **Gate Charge Test Circuit:**



### **Switching Time Test Circuit:**



### **Switching Waveforms:**



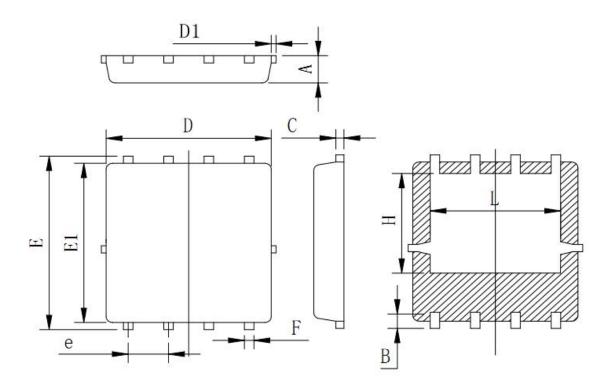
**Version: Preliminary** 

### Notes:

- ①Calculated continuous current based on maximum allowable junction temperature.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- $\ \ \,$  The power dissipation  $P_D$  is based on max. junction temperature, using junction-to-case thermal resistance.



# **Mechanical Data:**



Symbol	Min	Тур	Max
Α	0.90	0.95	1.00
В	0.48	0.58	0.68
C	0.20	0.254	0.30
D	5.00	5.20	5.40
D1			0.15
Е	5.90	6.05	6.20
El	5.40	5.55	5.70
e	1.22	1.27	1.32
F	0.25	0.30	0.35
Н	3.27	3.47	3.67
L	3.80	4.00	4.20





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